Notice of References Cited

- 1	Application/Control No. 10/604,794	Reexamination	Applicant(s)/Patent Under Reexamination CHEN ET AL		
Ţī	Examiner	Art Unit			
	Alexander O Williams	2826	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0185733 A1	12-2002	Chow et al.	257/737
	В	US-2003/0057551 A1	03-2003	Datta et al.	257/737
	c	US-6,417,089 B1	07-2002	Kim et al.	438/612
	D	US-6,501,185 B1	12-2002	Chow et al.	257/780
	Е	US-6,413,851 B1	07-2002	Chow et al.	438/613
	F	US-2004/0035909 A1	02-2004	Yeh et al.	228/56.3
	G	US-2003/0164552 A1	09-2003	Tong et al.	257/779
	Н	US-2003/0219987 A1	11-2003	Wang et al.	438/720
	1	US-			1007720
	J	US-	1.7		
	к	US-	5 (3)		
	L	US-		The state of the s	
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

1	The state of the s					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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1 000	are of Ale:					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.